

Notice of References Cited	Application/Control No. 10/584,156		Applicant(s)/Patent Under Reexamination SCHNEIDER ET AL.	
	Examiner Binh X. Tran		Art Unit 1792	Page 1 of 1

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*	B	US-2003/0188963	10-2003	Takikawa et al.	204/164
*	C	US-2003/0148097	08-2003	Takikawa et al.	428/364
*	D	US-2003/0111334	06-2003	Dodelet et al.	204/164
*	E	US-2003/0082094	05-2003	Loutfy et al.	423/447.3
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Wikipedia, "Transmission Electron Microscopy", http://en.wikipedia.org/wiki/Transmission_electron_microscope
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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